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DSCC FORM 2233 APR 97 <u>DISTRIBUTION STATEMENT A</u>. Approved for public release; distribution is unlimited.

5962-E238-01

1. SCOPE 查询:5962-9170001日XC"供应款 G (lowered high reliability), class H (high reliability), and class finishes which are available and are reflected in the Part or Ide hardness assurance levels are reflected in the PIN.	K, (highest reliabili	ty) and a choice of case of	outlines and lead					
1.2 <u>PIN</u> . The PIN shall be as shown in the following examp	le:							
5 <u>9</u> 62 - 91700 01	н	Х	Х					
Federal RHA Device   stock class designator type	Device class	Case	Lead finish					
designator (see 1.2.1) (see 1.2.2	2) designa	tor (see 1.2.4)	(see 1.2.5)					
Drawing number	(see 1.2	.3)						
1.2.1 Radiation hardness assurance (RHA) designator. RH	IA marked devices	shall meet the MIL-PRF-3	38534 specified RHA					
levels and shall be marked with the appropriate RHA designat								
1.2.2 <u>Device type(s)</u> . The device type(s) identify the circuit Device type Generic numbe		<u>Circuit functio</u>	on					
01 PA09M, MIOP42	_	Power operational						
1.2.3 <u>Device class designator</u> . This device class designato follows:	C C		ict assurance ievel as					
	performance docur							
D, E, G, H, or K Certification and qualification to MIL-PRF-38534								
1.2.4 <u>Case outline(s)</u> . The case outline(s) are as designate	1.2.4 Case outline(s). The case outline(s) are as designated in MIL-STD-1835 and as follows:							
Outline letter Descriptive designator	Terminals	Package styl	le					
X See figure 1	8	Flange mour	nt					
1.2.5 Lead finish. The lead finish shall be as specified in M	IL-PRF-38534.							
1.3 Absolute maximum ratings.								
Supply voltage (V <sub>S</sub> ) Output current (I <sub>O</sub> ) Power dissipation (P <sub>D</sub> ) $\underline{1}$ / Input voltage (differential) Input voltage (common mode) Lead temperature (soldering, 10 seconds) Junction temperature (T <sub>J</sub> ) Storage temperature range 1.4 <u>Recommended operating conditions</u> .	5.0 A 78 W ±40 V ±40 V ±40 V +300° +150°	dc dc C						
Supply voltage (Vs)Case operating temperature range (Tc)		dc to +125°C						
<u>1</u> / Derate at 1.8°C/W above case temperature (T <sub>c</sub> ) of +25°C.								
STANDARD	SIZE							
MICROCIRCUIT DRAWING	A		5962-91700					
DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000		REVISION LEVEL A	SHEET 2					

# 2. APPLICABLE DOCUMENTS

询"5962-9170001HXC"供应商 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those listed in the issue of the Department of Defense Index of Specifications and Standards (DoDISS) and supplement thereto, cited in the solicitation.

#### **SPECIFICATION**

DEPARTMENT OF DEFENSE

MIL-PRF-38534 - Hybrid Microcircuits, General Specification for.

**STANDARDS** 

DEPARTMENT OF DEFENSE

MIL-STD-883	-	Test Method Standard Microcircuits.
MIL-STD-1835	-	Interface Standard for Electronic Component Case Outlines.

#### HANDBOOKS

DEPARTMENT OF DEFENSE

MIL-HDBK-103 - List of Standard Microcircuit Drawings. MIL-HDBK-780 - Standard Microcircuit Drawings.

(Unless otherwise indicated, copies of the specification, standards, and handbooks are available from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

#### 3. REQUIREMENTS

3.1 Item requirements. The individual item performance requirements for device classes D, E, G, H, and K shall be in accordance with MIL-PRF-38534. Compliance with MIL-PRF-38534 may include the performance of all tests herein or as designated in the device manufacturer's Quality Management (QM) plan or as designated for the applicable device class. Therefore, the tests and inspections herein may not be performed for the applicable device class (see MIL-PRF-38534). Furthermore, the manufacturer may take exceptions or use alternate methods to the tests and inspections herein and not perform them. However, the performance requirements as defined in MIL-PRF-38534 shall be met for the applicable device class.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38534 and herein.

3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.4 herein and figure 1.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 2.

3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.

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3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical test **接触变动变动变动变动变动**。

3.5 <u>Marking of device(s)</u>. Marking of device(s) shall be in accordance with MIL-PRF-38534. The device shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's vendor similar PIN may also be marked in MIL-HDBK-103 and QML-38534.

3.6 <u>Data</u>. In addition to the general performance requirements of MIL-PRF-38534, the manufacturer of the device described herein shall maintain the electrical test data (variables format) from the initial quality conformance inspection group A lot sample, for each device type listed herein. Also, the data should include a summary of all parameters manually tested, and for those which, if any, are guaranteed. This data shall be maintained under document revision level control by the manufacturer and be made available to the preparing activity (DSCC-VA) upon request.

3.7 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to supply to this drawing. The certificate of compliance (original copy) submitted to DSCC-VA shall affirm that the manufacturer's product meets the performance requirements of MIL-PRF-38534 and herein.

3.8 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-PRF-38534 shall be provided with each lot of microcircuits delivered to this drawing.

#### 4. QUALITY ASSURANCE PROVISIONS

4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with MIL-PRF-38534 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.

4.2 <u>Screening</u>. Screening shall be in accordance with MIL-PRF-38534. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
  - (1) Test condition D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DSCC-VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.
  - (2) T<sub>C</sub> as specified in accordance with table I of method 1015 of MIL-STD-883.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- c. Constant acceleration may be performed after burn-in upon approval by the qualifying activity.

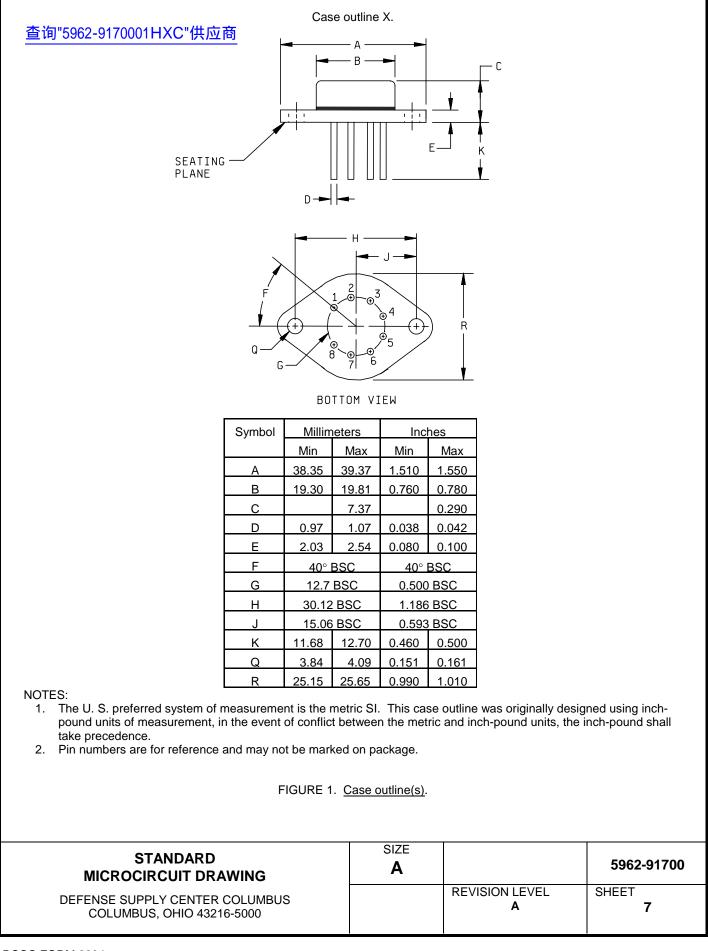
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<u>查询"5962-91700</u>	01HXC"(	TABLE I. <u>Electrical pe</u> 其应商	rformance cl	naracteristic	<u>&gt;s</u> .			I
Test	Symbol	Conditions <u>1</u> / -55°C $\leq$ T <sub>C</sub> $\leq$ +125° V <sub>S</sub> = ±35 dc	C s	Group A subgroups	Device type	Lim	its	Unit
		unless otherwise spec	cified			Min	Max	
Supply current	Is	$\label{eq:VIN} \begin{array}{l} V_{\text{IN}}=0 \ V \ dc, \ G=100, \\ V_{\text{CM}}=0 \ V \ dc \end{array}$		1 2 3	01		85 140 165	mA
Input offset voltage	V <sub>os</sub>	$\label{eq:VIN} \begin{array}{l} V_{\text{IN}}=0 \ V \ dc, \ G=100, \\ V_{\text{S}}=\pm 12 \ V \ dc \end{array}$		1 2 3	01	-5.3 -8.3 -7.7	+5.3 +8.3 +7.7	mV
		$\label{eq:VIN} \begin{array}{l} V_{\text{IN}}=0 \ V \ dc, \ G=100, \\ V_{\text{S}}=\pm 35 \ V \ dc \end{array}$		1 2 3		-3.0 -6.0 -5.4	+3.0 +6.0 +5.4	mV
		$\label{eq:VIN} \begin{array}{l} V_{\text{IN}}=0 \ V \ dc, \ G=100, \\ V_{\text{S}}=\pm 40 \ V \ dc \end{array}$		1 2 3		-3.5 -6.5 -5.9	+3.5 +6.5 +5.9	mV
Input bias current, +I <sub>N</sub>	+l <sub>B</sub>	$V_{\text{IN}}$ = 0 V dc, $R_{\text{BIAS}} \le 100$ M	ΔΩ	1,3	01		100	рА
				2			10.0	nA
Input bias current, $-I_N$	-I <sub>B</sub>	$V_{\text{IN}} = 0 \text{ V dc},  R_{\text{BIAS}} \leq 100  \text{M}$	<i>Μ</i> Ω	1,3	01		100	pА
				2			10.0	nA
Input offset current	l <sub>os</sub>	$V_{IN}$ = 0 V dc, $R_{BIAS} \le 100$ M	ΔΩ	1,3 2	01		50.0 10.0	pA nA
Output voltage	Vo	$V_{S} = \pm 40 \text{ V dc}, I_{O} = 66 \text{ mA}$ $R_{L} = 500 \Omega$	13	4,5,6	01	33		V
		$V_{S} = \pm 23.5 \text{ V dc}, I_{O} = 1 \text{ A},$ $R_{L} = 15 \Omega, T_{C} = +125^{\circ}\text{C}$		5		15		V
		$V_{S} = \pm 38 \text{ V dc}, I_{O} = 2 \text{ mA},$ $R_{L} = 15 \Omega, T_{C} = +25^{\circ}\text{C}, -50^{\circ}\text{C}$	55°C	4,6		30		V
		$\label{eq:VS} \begin{split} V_{S} &= \pm 21.3 \ V \ dc, \ I_{O} = 3 \ A, \\ R_{L} &= 3.75 \ \Omega, \ T_{C} = +25^{\circ}C, \end{split}$	-55°C	4,6		11.3		V
See footnotes at end of	STANDA	RD	SIZE				5062	-91700
MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000			A	RE	VISION LEV A	EL	SHEET	5

<u> </u>		TABLE I. <u>Electrical performance cha</u> 供应商		1			·
Test	Symbol	Conditions <u>1</u> / -55°C $\leq$ T <sub>C</sub> $\leq$ +125°C V <sub>S</sub> = ±35 V dc	Group A subgroups	Device type	Lir	Limits	
		unless otherwise specified			Min	Max	
Current limits	I <sub>CL</sub>	$\label{eq:RL} \begin{array}{l} R_{L} = 3.75 \; \Omega, \; V_{S} = \pm 32.2 \; V \; dc, \\ T_{C} = +25^{\circ}C \end{array}$	4	01	3.4	6	mA
Stability/noise	E <sub>N</sub>	G = 1, C <sub>L</sub> = 1.5 nF	4,5,6	01		1.0	mV
Slew rate	S <sub>R</sub>	$R_L = 500 \ \Omega, \ V_{IN} \geq 4 \ V_{P-P}$	4,6	01	25	500	V/µs
			5		20	500	
Open loop gain	A <sub>OL</sub>	$\label{eq:RL} \begin{split} R_L &= 500 \ \Omega, \ f = 15 \ Hz, \\ V_{IN} &\geq 0.4 \ V_{P-P} \end{split}$	4,5,6	01	80		dB
Common mode rejection	CMR	$V_{S} = \pm 34.5 \text{ V dc}, \text{ f} = \text{dc},$ $V_{CM} = \pm 22.5 \text{ V dc}$	4,5,6	01	64		dB

1/ During all group A testing, terminal connection BAL (pin 2) is left open.

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查询"5962-9170001HXC"供应商

Device type	01
Case outline	Х
Terminal number	Terminal symbol
1	Output
2	Balance (BAL)
3	+Vs
4	+IN
5	-IN
6	-Vs
7	R∟
8	CL

FIGURE 2. Terminal connections.

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5962-9170001HXC"	TABLE II. <u>Electrical test rec</u> '供应商	quirements.
	MIL-PRF-38534 test requirements	Subgroups (in accordance with MIL-PRF-38534, group A test table)
	Interim electrical parameters	
	Final electrical parameters	1*, 2, 3, 4, 5, 6
	Group A test requirements	1, 2, 3, 4, 5, 6
	Group C end-point electrical parameters	1, 4
	End-point electrical parameters for radiation hardness assurance (RHA) devices	Not applicable

\* PDA applies to subgroup 1.

4.3 <u>Conformance and periodic inspections</u>. Conformance inspection (CI) and periodic inspection (PI) shall be in accordance with MIL-PRF-38534 and as specified herein.

- 4.3.1 Group A inspection (CI). Group A inspection shall be in accordance with MIL-PRF-38534 and as follows:
  - a. Tests shall be as specified in table II herein.
  - b. Subgroups 7, 8, 9, 10, and 11 shall be omitted.
- 4.3.2 Group B inspection (PI). Group B inspection shall be in accordance with MIL-PRF-38534.
- 4.3.3 Group C inspection (PI). Group C inspection shall be in accordance with MIL-PRF-38534 and as follows:
  - a. End-point electrical parameters shall be as specified in table II herein.
  - b. Steady-state life test, method 1005 of MIL-STD-883.
    - (1) Test condition D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DSCC-VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
    - (2) T<sub>C</sub> as specified in accordance with table I of method 1005 of MIL-STD-883.
    - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.
- 4.3.4 Group D inspection (PI). Group D inspection shall be in accordance with MIL-PRF-38534.
- 4.3.5 Radiation Hardness Assurance (RHA) inspection. RHA inspection is not currently applicable to this drawing.

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## 5. PACKAGING

<sup>[</sup> <mark>近日: 1 Packaging requirements: The requ</mark>irements for packaging shall be in accordance with MIL-PRF-38534.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractorprepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-PRF-38534.

6.4 Record of users. Military and industrial users shall inform Defense Supply Center Columbus when a system application requires configuration control and the applicable SMD. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0544.

6.5 Comments. Comments on this drawing should be directed to DSCC-VA, Post Office Box 3990, Columbus, Ohio 43216-5000, or telephone (614) 692-0512.

6.6 Sources of supply. Sources of supply are listed in MIL-HDBK-103 and QML-38534. The vendors listed in MIL-HDBK-103 and QML-38534 have submitted a certificate of compliance (see 3.7 herein) to DSCC-VA and have agreed to this drawing.

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### 查询"5962-9170001HXC"供应商NDARD MICROCIRCUIT DRAWING BULLETIN

#### DATE: 01-02-14

Approved sources of supply for SMD 5962-91700 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38534 during the next revisions. MIL-HDBK-103 and QML-38534 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This bulletin is superseded by the next dated revisions of MIL-HDBK-103 and QML-38534.

Standard	Vendor	Vendor
microcircuit drawing	CAGE	similar
PIN <u>1</u> /	number	PIN <u>2</u> /
5962-9170001HXA	31757	MIOP42119/883
5962-9170001HXC	31757	MIOP42119/883
5962-9170001HXA	60024	PA09M/883
5962-9170001HXC	60024	PA09M/883

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the Vendor to determine its availability.
- 2/ <u>Caution</u>. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number	Vendor name and address
31757	Micropac Industries, Incorporated 905 E. Walnut Street Garland, TX 75040 Point of contact: 912 E. Walnut Street Garland, TX 75040
60024	Apex Microtechnology Corporation 5980 N. Shannon Road Tucson, AZ 85741

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